

April 1988 Revised August 1999

74F533

Octal Transparent Latch with 3-STATE Outputs

General Description

The 74F533 consists of eight latches with 3-STATE outputs for bus organized system applications. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the setup times is latched. Data appears on the bus when the Output Enable (\overline{OE}) is LOW. When \overline{OE} is HIGH the bus output is in the high impedance state. The 74F533 is the same as the 74F373, except that the outputs are inverted.

Features

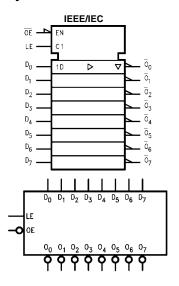
- Eight latches in a single package
- 3-STATE outputs for bus interfacing
- Inverted version of the 74F373

Ordering Code:

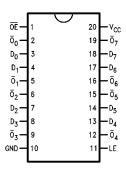
Order Number	Package Number	Package Description
74F533SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F533SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F533PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}		
	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
D ₀ –D ₇	Data Inputs	1.0/1.0	20 μA/-0.6 mA		
LE	Latch Enable Input (Active HIGH)	1.0/1.0	20 μA/-0.6 mA		
ŌĒ	Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA		
\overline{O}_0 – \overline{O}_7	Complementary 3-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)		

Function Table

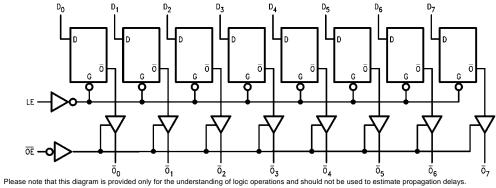
	Inputs			
LE	OE	D	ō	
Н	L	Н	L	
Н	L	L	Н	
L	L	X	\overline{O}_0	
Х	Н	X	Z	

- H = HIGH Voltage Level
- L = LOW Voltage Level
- X = Immaterial

Functional Description

The 74F533 contains eight D-type latches with 3-STATE output buffers. When the Latch Enable (LE) input is HIGH, data on the $D_{\rm n}$ inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D input changes. When LE is LOW, the latches store the information that was present on the D inputs a setup time preceding the HIGH-to-LOW transition of LE. The 3-STATE buffers are controlled by the Output Enable (OE) input. When OE is LOW, the buffers are in the bi-state mode. When OE is HIGH the buffers are in the high impedance mode but this does not interfere with entering new data into the latches.

Logic Diagram



Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

 $\begin{array}{ll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \end{array}$

Junction Temperature under Bias -55°C to +125°C -55°C to +150°C

V_{CC} Pin Potential to

 $\begin{array}{lll} \mbox{Ground Pin} & -0.5 \mbox{V to } +7.0 \mbox{V} \\ \mbox{Input Voltage (Note 2)} & -0.5 \mbox{V to } +7.0 \mbox{V} \\ \mbox{Input Current (Note 2)} & -30 \mbox{ mA to } +5.0 \mbox{ mA} \\ \end{array}$

Voltage Applied to Output in HIGH State (with V_{CC} = 0V)

 $\begin{array}{ll} \text{Standard Output} & -0.5 \text{V to V}_{\text{CC}} \\ \text{3-STATE Output} & -0.5 \text{V to } +5.5 \text{V} \end{array}$

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA) ESD Last Passing Voltage (Min) 4000V

Free Air Ambient Temperature $0^{\circ}\text{C to } +70^{\circ}\text{C}$ Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

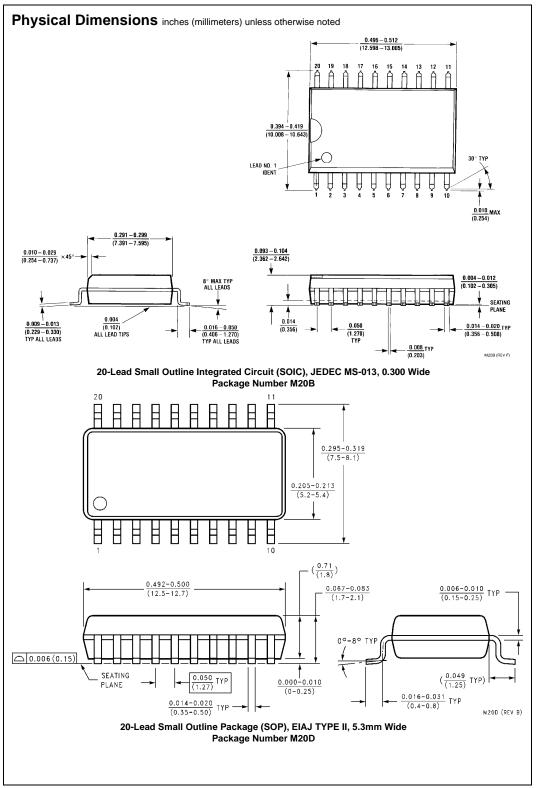
Symbol	I Parameter		Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Volt	age			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.5					I _{OH} = -1 mA
	Voltage	10% V _{CC}	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
		5% V _{CC}	2.7			V		$I_{OH} = -1 \text{ mA}$
		5% V _{CC}	2.7					$I_{OH} = -3 \text{ mA}$
V _{OL}	Output LOW Voltage	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA
I _{IH}	Input HIGH Current				5.0	μΑ	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current				7.0	^	May	V 70V
	Breakdown Test			7.0	μА	Max	V _{IN} = 7.0V	
I _{BVIT}	Input HIGH Current				0.5	mA	May	V 55V
	Breakdown (I/O)				0.5	mA	Max	V _{IN} = 5.5V
I _{CEX}	Output HIGH				50	μА	Max	V _{OLIT} = V _{CC}
	Leakage Current				30	μА	IVIAX	VOUT = VCC
V _{ID}	Input Leakage		4.75			V		$I_{ID} = 1.9 \mu A$
	Test		4.75			V	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75	μА	A 0.0	V _{IOD} = 150 mV
	Circuit Current				3.73	μА	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$
I _{OZH}	Output Leakage Currer	nt			50	μА	Max	V _{OUT} = 2.7V
I _{OZL}	Output Leakage Currer	nt			-50	μΑ	Max	V _{OUT} = 0.5V
Ios	Output Short-Circuit Cu	irrent	-60		-150	mA	Max	V _{OUT} = 0V
I _{ZZ}	Bus Drainage Test				500	μА	0.0V	V _{OUT} = 5.25V
I _{CCZ}	Power Supply Current			41	61	mA	Max	V _O = HIGH Z

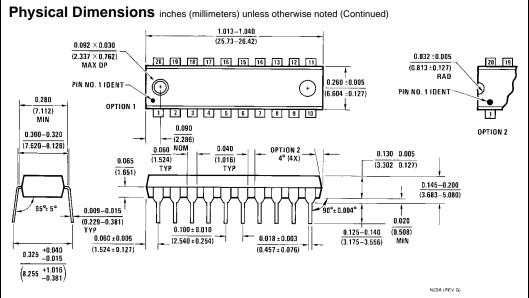
AC Electrical Characteristics

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_A = -55 ^{\circ} C \text{ to } +125 ^{\circ} C$ $V_{CC} = +5.0 V$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	4.0	6.7	9.0	4.0	12.0	4.0	10.0	
t _{PHL}	D_n to \overline{O}_n	2.5	4.4	7.0	2.5	9.0	2.5	8.0	ns
t _{PLH}	Propagation Delay	5.0	7.1	11.0	5.0	14.0	5.0	13.0	
t _{PHL}	LE to \overline{O}_n	3.0	4.7	7.0	3.0	9.0	3.0	8.0	ns
t _{PZH}	Output Enable Time	2.0	5.9	10.0	2.0	12.5	2.0	11.0	
t _{PZL}		2.0	5.6	7.5	2.0	10.5	2.0	8.5	ns
t _{PHZ}	Output Disable Time	1.5	3.4	6.5	1.5	8.5	1.5	7.0	ns
t _{PLZ}		1.5	2.7	5.5	1.5	7.5	1.5	6.5	115

AC Operating Requirements

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$		$T_A = -55^{\circ}C$ to $+125^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units
		Min	Max	Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	2.0		2.0		2.0		
t _S (L)	D _n to LE	2.0		2.0		2.0		ns
t _H (H)	Hold Time, HIGH or LOW	3.0		3.0		3.0		
t _H (L)	D _n to LE	3.0		3.0		3.0		ns
t _W (H)	LE Pulse Width, HIGH	6.0		6.0		6.0		ns





20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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